



SHEET 1 OF 1

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
250917US3CONTSERIAL NO.
10/830,101

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Junichi MATSUMOTO, et al.

FILING DATE
April 23, 2004GROUP
2852

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
AF	2004-046268	2/2004	JAPAN (w/abstract)			
AG	09-166912	6/1997	JAPAN (w/abstract)			
AH	64-17550	1/1989	JAPAN		X	
AI	2001-175083	6/2001	JAPAN (w/abstract)			
AJ	1-24739	1/1986	JAPAN		X	
AK	11-272075	10/1999	JAPAN (w/abstract)			
AL	10-063087	3/1998	JAPAN (w/abstract)			
AM	04-143781	5/1992	JAPAN (w/abstract)			
AN	58-123444	8/1983	JAPAN		X	
AO	10-293452	11/1998	JAPAN (w/abstract)			
AP	04-134471	5/1992	JAPAN (w/abstract)			
AQ	09-022175	1/1997	JAPAN (w/abstract)			
AR	10-097130	4/1998	JAPAN (w/abstract)			
AS	09-292773	11/1997	JAPAN (w/abstract)			
AT	2000-227706	8/15/2000	JAPAN (w/abstract)			
AU	60-3856	1/12/1985	JAPAN		X	
AV						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

AW	
AX	
AY	
AZ	<input type="checkbox"/> Additional References sheet(s) attached

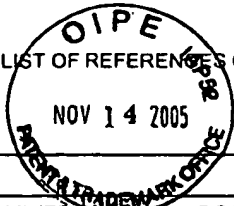
Examiner

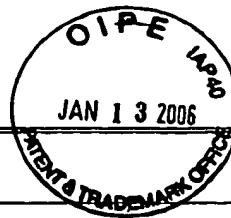
R Beatty

Date Considered

4/3/06

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 250917US3CONT		SERIAL NO. 10/830,101	
				APPLICANT Junichi MATSUMOTO, et al.			
				2 ND RCE FILING DATE August 11, 2005		GROUP 2852	
				U.S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
RCS	AA	5,740,507	04/14/1998	Ichikawa et al.	2		
	AB	5,655,195	08/05/1997	Ichikawa et al.			
	AC	5,074,342	12/24/1991	Kraehn			
	AD	5,915,154	06/22/1999	Schoch et al.			
	AE	5,570,170	10/29/1996	Muranyi et al.			
	AF	4,274,455	06/23/1981	Simons			
	AG	4,945,956	08/07/1990	Bueyuekgueclue et al.			
	AH	4,503,625	03/12/1985	Manzer			
	AI	5,848,326	12/08/1998	Komuro et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
RCS	AJ	JP2000-128192	05/09/2000	Japan (w/ English abstract)		x	
	AK	EP1014214	06/28/2000	EPO			
	AL	EP1193570	04/03/2002	EPO			
	AM	JP08-211723	08/20/1996	Japan (w/ English abstract)		x	
	AN	JP06-59572	03/04/1994	Japan (w/ English abstract)		x	
	AO	JP03-241372	10/28/1991	Japan (w/ English abstract)		x	
	AU	JP08-292636	11/05/1996	Japan (w/ English abstract)		x	
	AV	JP02-053055	02/22/1990	Japan (w/ English abstract)		x	
	AW	JP08-314272	11/29/1996	Japan (w/ English abstract)		x	
	AX	JP04-087901	03/19/1992	Japan (w/ English abstract)		x	
	AY	JP09-106156	04/22/1997	Japan (w/ English abstract)		x	
	AZ	JP61-059464	03/26/1986	Japan (w/ English abstract)		x	
	AAA	JP64-052181	02/28/1989	Japan (w/ English abstract)		x	
	AAB	JP08-171281	07/02/1996	Japan (w/ English abstract)		x	
	AAC	JP05-232810	09/10/1993	Japan (w/ English abstract)		x	
	AAD	JP57-057451	04/06/1982	Japan (w/ English abstract)		x	
	AAE	JP06-208301	07/26/1994	Japan (w/ English abstract)		x	
	AAF	JP07-261529	10/13/1995	Japan (w/ English abstract)		x	
AAG	JP06-191049	07/12/1994	Japan (w/ English abstract)		x		
AAH	JP09-305080	11/28/1997	Japan (w/ English abstract)		x		
					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner <i>R. Beatty</i>					Date Considered <i>9/3/06</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
MB	AA	5,740,507	4/14/98	Ichikawa et al.			
	AB	5,655,195	8/5/97	Ichikawa et al.			
	AC	5,950,055	9/7/99	Yahata et al.			
	AD	5,915,154	6/22/99	Schoch et al.			
	AE	5,570,170	10/29/96	Muranyi et al.			
	AF	4,274,455	6/23/81	Simons			
	AG	4,945,956	8/7/90	Bueyuekguedue et al.			
	AH	4,503,625	3/12/85	Manzer			
	AI	5,848,326	12/8/98	Komuro et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
MB	AJ	JP 2000-128192	May-2000	JAPAN (w/abstract)			X
	AK	EP 1,014,214	Jun-2005	EUROPEAN			
	AL	EP 1,193,570	Nov-2004	EUROPEAN			
	AM	JP 08-211723	Aug-1996	JAPAN (w/abstract)			X
	AN	JP 03-241372	Oct-1991	JAPAN (w/abstract)			X
	AO	JP 08-292636	Nov-1996	JAPAN (w/abstract)			X
	AP	JP 02-053055	Feb-1990	JAPAN (w/abstract)			X
	AQ	JP 08-314272	Nov-1996	JAPAN (w/abstract)			X
	AR	JP 04-087901	Mar-1992	JAPAN (w/abstract)			X
	AS	JP 09-106156	Apr-1997	JAPAN (w/abstract)			X
	AT	JP 61-059464	Mar-1986	JAPAN (w/abstract)			X
	AU	JP 64-052181	Feb-1989	JAPAN (w/abstract)			X
	AV	JP 08-171281	Jul-1996	JAPAN (w/abstract)			X
	AW	JP 05-232810	Sep-1993	JAPAN (w/abstract)			X
	AX	JP 57-057451	Apr-1982	JAPAN (w/abstract)			X
	AY	JP 06-208301	Jul-1994	JAPAN (w/abstract)			X
	AZ	JP 07-261529	Oct-1995	JAPAN (w/abstract)			X
	AAA	JP 06-191049	Jul-1994	JAPAN (w/abstract)			X
AAB	JP 09-305080	Nov-1997	JAPAN (w/abstract)			X	
AAC	JP 06-059572	Mar-1994	JAPAN (w/abstract)			X	
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